

Form PTO 1449
(Modified)DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
251241US2SERIAL NO.
10/812,887

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Katsufumi EHATAFILING DATE
March 31, 2004

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN			none <i>JH</i>			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>JH</i>	AO	6-138076	05/20/1994	JAPAN		X
	AP			Reconsidered 2/30/06		
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV			none <i>JH</i>		

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>JH</i>	AW	Y. IJIMA, pages 20-23, "ELECTRONIC MONTHLY", 1998
<i>JH</i>	AX	JIS R 1627, Japanese Standards Association, pages 1-18, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMICS AT MICROWAVE FREQUENCY", July 1996
<i>JH</i>	AY	JIS R 1641, Japanese Standards Association, pages 1-29, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMIC PLATES AT MICROWAVE FREQUENCY", January 2002
	AZ	none

☐ Additional References sheet(s) attached

Examiner

Jeff Hatalini

Date Considered

8/19/05

*Examiner: Initial reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.